PALM INTRANET

Inventor Name Search Result

Your Search was:

Last Name = KUND
First Name = MICHAEL

Inventor Search PM 09/193646

Application#	Patent#	Status	Date Filed	Title	Inventor Name
10195598	Not Issued	030	07/11/2002	TEST METHOD AND TEST DEVICE FOR ELECTRONIC MEMORIES	KUND, MICHAEL
10164770	Not Issued	030	06/07/2002	DEVICE FOR AND METHOD OF EXAMINING THE SIGNAL PERFORMANCE OF SEMICONDUCTOR CIRCUITS	KUND, MICHAEL
10000691	Not Issued	071	11/15/2001	CONFIGURATION AND METHOD FOR INCREASING THE RETENTION TIME AND THE STORAGE SECURITY IN A FERROELECTRIC OR FERROMAGNETIC SEMICONDUCTOR MEMORY	KUND, MICHAEL
09931686	Not Issued	071	08/16/2001	APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION AND CHARACTERIZATION OF TEST ADAPTERS	KUND, MICHAEL
09705599	Not Issued	083	11/03/2000	NEEDLE-CARD ADJUSTING DEVICE FOR PLANARIZING NEEDLE SETS ON A NEEDLE CARD	KUND, MICHAEL
09642734	6256243	150	08/17/2000	TEST CIRCUIT FOR TESTING A DIGITAL SEMICONDUCTOR CIRCUIT CONFIGURATION	KUND, MICHAEL
09313422	6359457	150	05/17/1999	METHOD OF HOLDING A WAFER AND TESTING THE INTEGRATED CIRCUITS ON THE WAFER	KUND , MICHAEL
09138416	6184524	150	08/24/1998	AUTOMATED SET UP OF	KUNDMANN ,

09138416	6184524	150	08/24/1998	AUTOMATED SET UP OF AN ENERGY FILTERING TRANSMISSION ELECTRON MICROSCOPE	KUNDMANN , MICHAEL KARL
08684973	5798524	150	08/07/1996	AUTOMATED ADJUSTMENT OF AN ENERGY FILTERING TRANSMISSION ELECTRON MICROSCOPE	KUNDMANN , MICHAEL K.

Inventor Search Completed: No Records to Display.

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Your Search was:

Last Name = APPEN
First Name = STEPHAN

Application#	Patent#	Status	Date Filed	Title	Inventor Name
09931686	Not Issued	071	08/16/2001	APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION AND CHARACTERIZATION OF TEST ADAPTERS	APPEN, STEPHAN

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Inventor Name Search Result

Your Search was:

Last Name = HUBNER
First Name = MICHAEL

Application#	Patent#	Status	Date Filed	Title	Inventor Name
10247575	Not Issued	030	09/19/2002	METHOD FOR REWIRING PADS IN A WAFER-LEVEL PACKAGE	HUBNER, MICHAEL
10105590	Not Issued	030	03/25/2002	METHOD FOR RELEASABLE CONTACT-CONNECTION OF A PLURALITY OF INTEGRATED SEMICONDUCTOR MODULES ON A WAFER	HUBNER, MICHAEL
10010504	Not Issued	041	12/05/2001	TEST CONFIGURATION AND TEST METHOD FOR TESTING A PLURALITY OF INTEGRATED CIRCUITS IN PARALLEL	HUBNER, MICHAEL
09931686	Not Issued	071	08/16/2001	APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION AND CHARACTERIZATION OF TEST ADAPTERS	HUBNER, MICHAEL

Inventor Search Completed: No Records to Display.

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L Number	Hits	Search Text	DB	Time stamp
-	1950	324/158.1.ccls.	USPAT; US-PGPUB	2003/06/25 16:00
-	2674	324/754-758.ccls.	USPAT; US-PGPUB	2003/02/06 12:55
-	292	324/158.1.ccls. and 324/754-758.ccls.	USPAT; US-PGPUB	2003/02/06 12:55
-	2	(324/158.1.ccls. and 324/754-758.ccls.) and step$ adj motor	USPAT; US-PGPUB	2003/02/06 12:56
-	2	(324/158.1.ccls. and 324/754-758.ccls.) and step$ adj motor	USPAT; US-PGPUB	2003/02/06 12:56
-	1	"20020030485"	USPAT; US-PGPUB	2003/02/07 15:11
-	1	"20020030480"	USPAT; US-PGPUB	2003/02/07 15:11
-	84	paresh.xa.	USPAT; US-PGPUB	2003/06/25 13:43
-	0	6411079.URPN.	USPAT	2003/06/25 13:49
-	4	("4417204" | "4820975" | "5177528" | "5525912").PN.	USPAT	2003/06/25 13:49
-	1	anjan.xa. and nishikawa.in.	USPAT; US-PGPUB	2003/06/25 14:00
-	0	6356093.URPN.	USPAT	2003/06/25 13:55
-	5	("4677474" | "4820975" | "4934064" | "4985676" | "5644245").PN.	USPAT	2003/06/25 13:55
-	230	hubner.in.	USPAT; US-PGPUB	2003/06/25 14:00
-	0	(michael adj hubner).in.	USPAT; US-PGPUB	2003/06/25 14:01
-	0	michael adj hubner	USPAT; US-PGPUB	2003/06/25 14:08
-	4	(("6256243") or ("6359457") or ("6184524") or ("5798524")).PN.	USPAT; US-PGPUB	2003/06/25 14:08
-	2	(test adj head and adjust$5 near2 pin).clm.	USPAT; US-PGPUB	2003/06/25 14:13
-	3	test adj head and adjust$5 near2 pin	EPO; JPO; DERWENT; IBM_TDB	2003/06/25 14:15
-	17	4589815.URPN.	USPAT	2003/06/25 14:18
-	1842	324/754.ccls.	USPAT; US-PGPUB	2003/06/25 14:30
-	351	324/754.ccls. and pin and adjust$5	USPAT; US-PGPUB	2003/06/25 14:30
-	1449	324/754.ccls.	EPO; JPO; DERWENT; IBM_TDB	2003/06/25 14:30
-	7	324/754.ccls. and pin and adjust$5	EPO; JPO; DERWENT; IBM_TDB	2003/06/25 14:30
-	434	324/754.ccls. and pin and adjust$5	USPAT; US-PGPUB	2003/06/25 14:38
-	184	324/754.ccls. and (pin probe) near2 adjust$5	USPAT; US-PGPUB	2003/06/25 15:28
-	2142	324/754,761.ccls.	USPAT; US-PGPUB	2003/06/25 15:28
-	205	324/754,761.ccls. and adjust$5 near2 (probe pin)	USPAT; US-PGPUB	2003/06/25 15:29
-	59	324/754,761.ccls. and adjust$5 adj (probe pin)	USPAT; US-PGPUB	2003/06/25 15:29
-	2	(("4471298") or ("4904934")).PN.	USPAT; US-PGPUB	2003/06/25 16:19
-	52	testing adj probe adj card	USPAT; US-PGPUB	2003/06/25 16:20
-	64	testing adj probe adj card	USPAT; US-PGPUB	2003/06/25 16:21
-	32	(testing adj probe adj card) and adjust$5	USPAT; US-PGPUB	2003/06/25 16:21